Search Notes

_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/785,263	YAMAGUCHI ET AL.	
	Examiner	Art Unit	
	Michelle K. Lay	2672	

SEARCHED						
Class	Subclass	Date	Examiner			
345	649-659	10/28/2005	MKL			
· · · · · · · · · · · · · · · · · · ·						

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
·			
	<u></u>	-	
		_	

SEAR (INCLUDING SE	CH NOTES)
		DATE	EXMR
Inventor search		8/30/2005	MKL
EAST search	1	0/28/2005	MKL
EAST search	1	0/31/2005	MKL
.			
	•		